

Modelling Solar Images from SDO/AIA with Denoising Diffusion Probabilistic Models

Machine Learning and Computer Vision in Heliophysics MCH23

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1 Introduction

2 The dataset

3 Experiments and Discussion

4 Results

5 Conclusion

Goal of the project

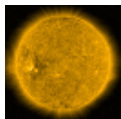
Machine Learning Goal

The goal of this project is to utilize generative models, specifically diffusion models, to produce images of the Sun with a specific amount of activity present.

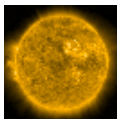
Why do we want to do this analysis?

Generate the rarest events (e.g., M- or X-flares) to solve the problem of the unbalanced dataset, being able to investigate these phenomena more extensively with more data.

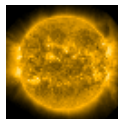
Generated Images



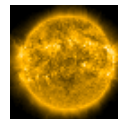
(a) A class



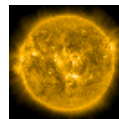
(b) B class



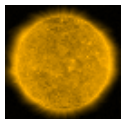
(c) C class



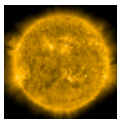
(d) M
class



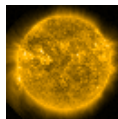
(e) X class



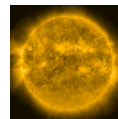
(f) A class



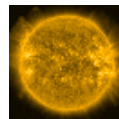
(g) B class



(h) C class



(i) M class



(j) X class

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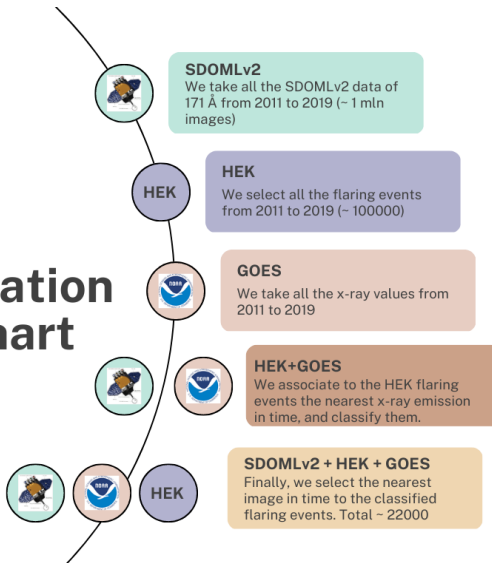
Data sources

We used three data sources:

- **SDOMLv2**: a subset of the SDO data already prepared for machine learning studies,
- **GOES X-Ray Sensor (XRS)**: soft X-ray measurements in the XRSB (1-8 Å) band,
- **Heliophysics Events Knowledgebase (HEK)**: peak time and GOES labels of flaring events.

Data Preparation

Data Preparation Flowchart



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What are the DDPMs?

Diffusion Probabilistic models are very popular nowadays and we can summarize their usage into the following bullet points:

- Forward process or noising process (Ho et al., 2020):

$$q(x_{1:T}|x_0) = \prod_{t=1}^T q(x_t|x_{t-1}), \quad q(x_t|x_{t-1}) = \mathcal{N}(x_t; \sqrt{1 - \beta_t}x_{t-1}, \beta_t\mathcal{I}) \quad (1)$$

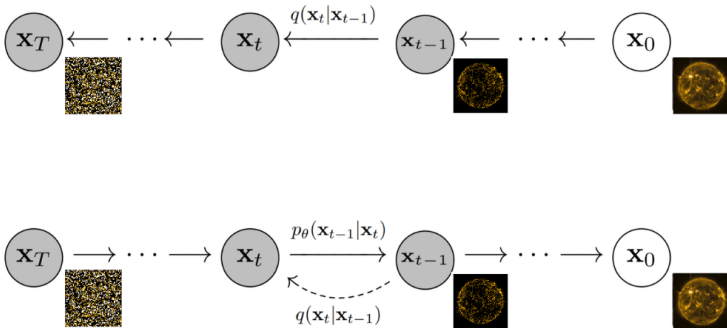
- Reverse process or denoising (Ho et al., 2020):

$$p_\theta(x_{t-1}|x_t) := \mathcal{N}(x_{t-1}; \mu_\theta(x_t, t), \Sigma_\theta(x_t, t)) \quad (2)$$

- Classifier Free Guidance (Ho Salimans, 2022)

$$\tilde{\epsilon}_\theta(z, c) = \epsilon_\theta(z, c) + w \cdot (\epsilon_\theta(z, c) - \epsilon_\theta(z)) \quad (3)$$

What are the DDPMs?



Adapted from Ho et al. 2020

Experiments setup and labelling systems

We use the following setup:

- Image resolution: 64x64,
- Number of Epochs: 500 (for each model),
- Batch size = 12.

We perform the following distinct experiments:

- Discrete labels: A, B, C, M and X,
- Continous labels: X-ray values,
- Discrete labels + ceVAE embeddings

We compare the results with the following baseline model:

- ceVAE (Giger M., 2022)

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Metrics

To evaluate the best model we used the following metrics:

- **Cluster Metrics** (Hackstein et al., 2023): determine if the generated distribution is similar to the true distribution. The cluster metrics can be divided into:
 - 1 Cluster Error (CE),
 - 2 Cluster Distance (CD),
 - 3 Cluster Standard Deviation (CS).
- **FID** (Heusel et al., 2017): determine the image quality level and the completeness of the generated distribution. The FID is computed using the following encoders:
 - 1 CLIP (Alec Radford et al., 2021),
 - 2 IV3 (Karras et al., 2020).
- **F1 score**: check whether the generated image of a particular class (e.g. X) is similar to a true image of that class.

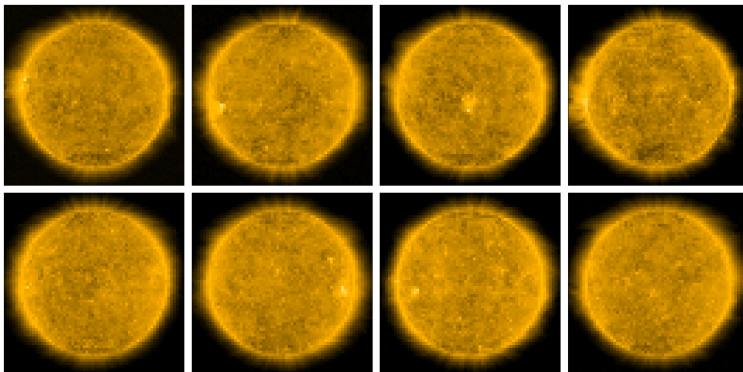
Metric Results

Metric	ceVAE	Discrete	Continuous	cevae_emb
CE GEN	7.948 $\pm$ 0.914	0.130 $\pm$ 0.036	1.503 $\pm$ 0.147	0.207 $\pm$ 0.036
CD GEN	2.206 $\pm$ 0.009	0.921 $\pm$ 0.004	0.934 $\pm$ 0.002	0.838 $\pm$ 0.005
CS GEN	3.239 $\pm$ 0.009	1.211 $\pm$ 0.004	1.098 $\pm$ 0.002	1.480 $\pm$ 0.005
FID CLIP	5.05	0.122	0.057	0.39
FID IV3	215.933	3.693	2.703	12.264
F1 score		0.7	0.34	0.6
Precision		0.73	0.35	0.6
Recall		0.74	0.37	0.7

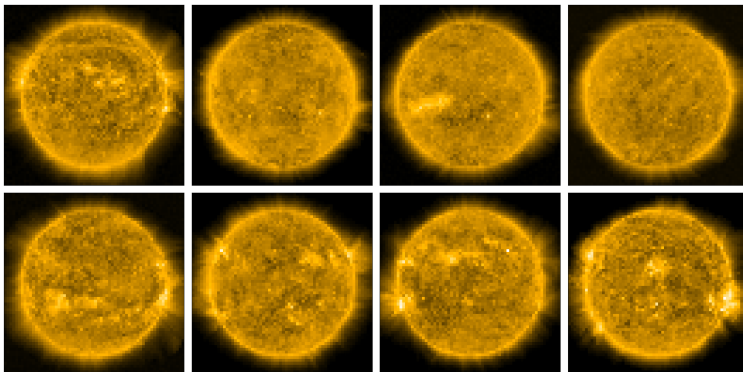
The benchmark values for the cluster metrics are:

- Cluster Error (CE): 0.002,
- Cluster Distance (CD): 1.001,
- Cluster Standard Deviation (CS): 0.998.

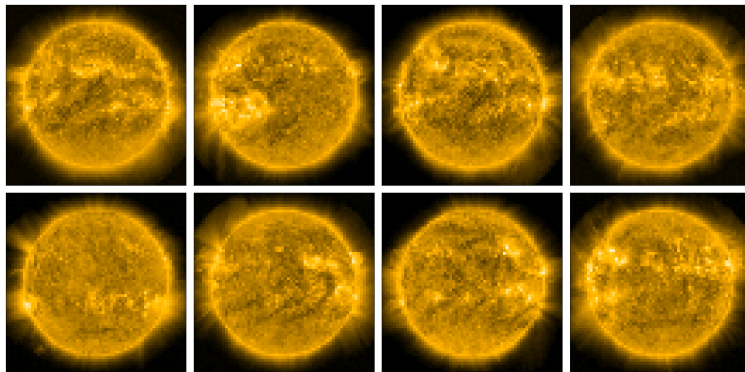
A



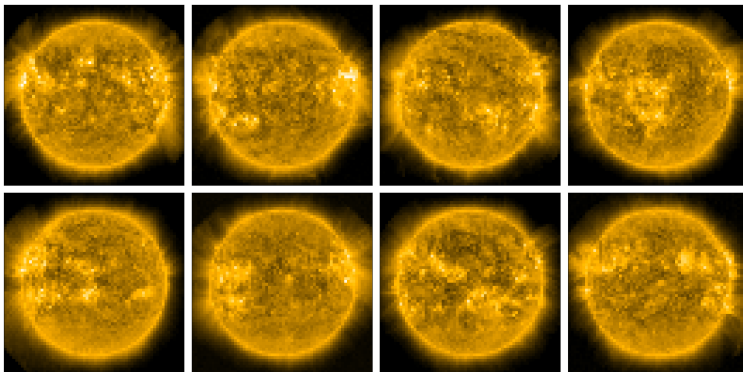
B



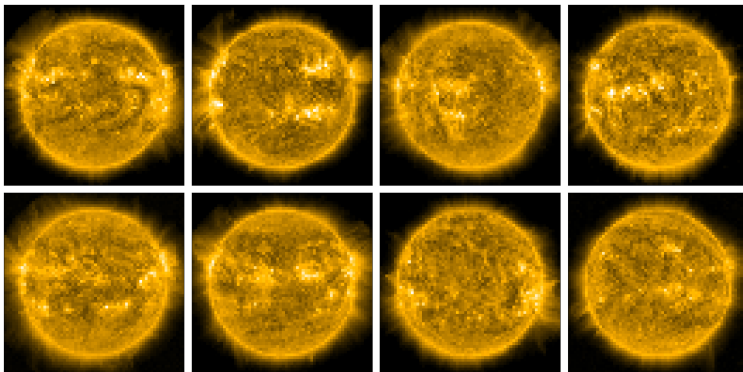
C



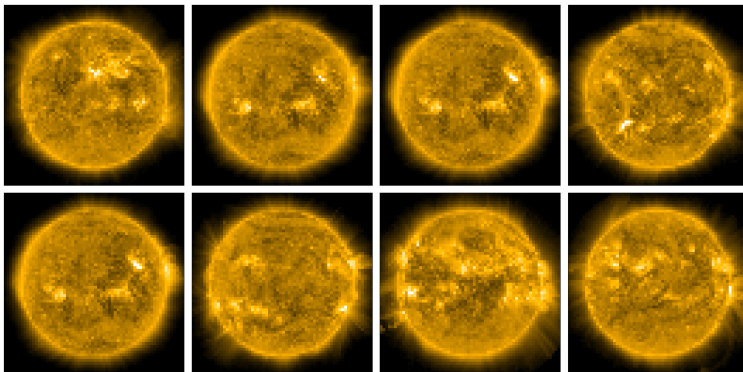
M



X



True X images



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Conclusion

- The best model to generate SDO/AIA images is the model guided with the discrete GOES labels
- It is possible to control the level of activity on top of the sun thanks to the labelling system that we adopted,
- It is possible to apply the generated images to manage the unbalanced dataset in a classifier and increase the accuracy per class,
- As future work, we would like to test it on other deep learning tasks (e.g., obtain the magnetograms of the generated images, solve the problems of the dataset, generate the flaring regions to zoom in only on the interested region, ...),
- The paper is in preparation.

Time for Questions!

The modern classification system for solar flares uses the letters A, B, C, M, or X, according to the peak flux in watts per square metre (W/m^2) of soft X-rays:

- A: $< 10^{-7}$
- B: $10^{-7} - 10^{-6}$
- C: $10^{-6} - 10^{-5}$
- M: $10^{-5} - 10^{-4}$
- X: $> 10^{-4}$



Classifier Free Guidance (CFG)

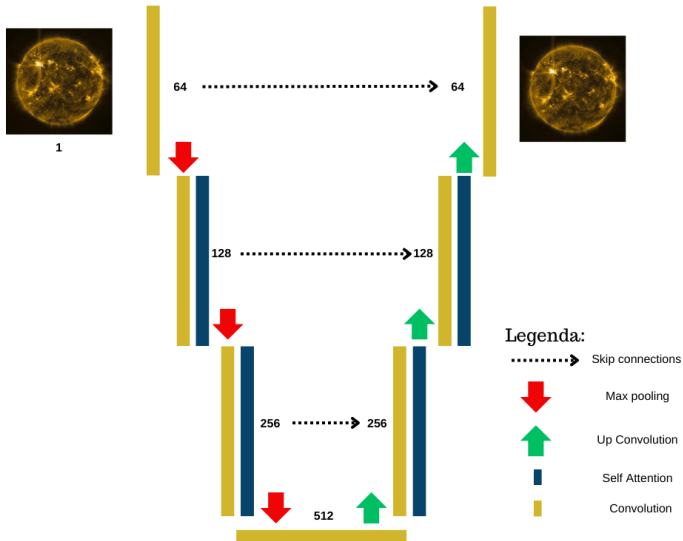
Credits: Outlier

Classifier Free Guidance (CFG)

- Guide the diffusion model with labels in order to be able to produce an image with a determined label,
- The idea is that you train it both unconditioned and conditioned and then interpolate between the two giving a weight to the conditioning in a way that you can direct the production towards that particular label space,
- The most important hyper-parameters are the:
 - ① ρ_c = probability of training with labels,
 - ② w = the CFG scale, the weight for the interpolation.

$$\tilde{\epsilon}_{\theta}(z, c) = \epsilon_{\theta}(z, c) + w \cdot (\epsilon_{\theta}(z, c) - \epsilon_{\theta}(z)) \quad (4)$$

Unet



Cluster Metrics

- Cluster Error:

①

$$\epsilon = \frac{1}{K} \sum_{c=1}^K K \frac{(\hat{n}_c - n_c)^2}{n_c^2} \quad (5)$$

We count the number of samples $\hat{n}_c$ in each of K clusters and compute the difference to the target n_c . This metric measures whether the interesting regions in feature space, i. e. the clusters, are populated with the same number of samples as in the target distribution. A value of 0 indicates a perfect match. Larger values indicate deviation from the target, i. e. over- and underproduction of some type.

Cluster Metrics

- Cluster Distance:

1

$$D = \frac{1}{d} \sqrt{\frac{1}{N} \sum_{i=1}^N \hat{d}_i^2} \quad (6)$$

We compute the distance $\hat{d}_i$ to the corresponding cluster center for each of N samples. Then, D is the normalized root-mean-square (RMS) of these distances. This metric measures whether the samples populate the correct regions in feature space with sufficient diversity. Values larger than 1 indicate that the sample contains images outside the target distribution.

Cluster Metrics

- Cluster Std:

1

$$S = \frac{1}{S_{target}} \sqrt{\frac{1}{N} \sum_{i=1}^N (\hat{d}_i - d \cdot D)^2} \quad (7)$$

For the distances to the cluster center $\hat{d}_i$, we further compute S as standard deviation from D.

FID

- FID:

- $$FID(x, g) = \|\mu_x - \mu_g\|^2 + \text{Tr}(\Sigma_x + \Sigma_g - 2(\Sigma_x \Sigma_g)^{(1/2)}),$$

- F1 score:

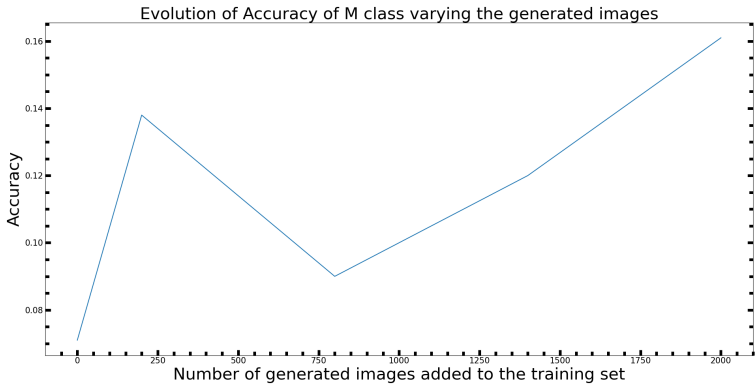
- $$F_1 = \frac{2 \times \text{Precision} \times \text{Recall}}{\text{Precision} + \text{Recall}}$$

- Precision and Recall:

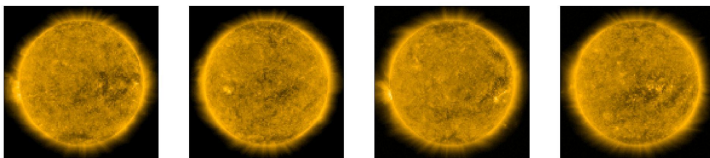
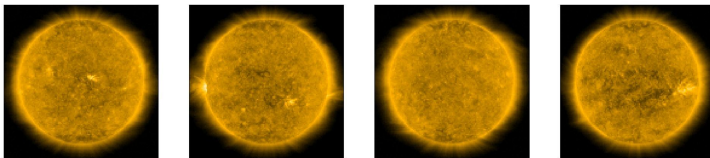
- $$P = \frac{TP}{TP + FP}$$

- $$R = \frac{TP}{TP + FN}$$

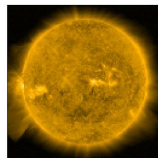
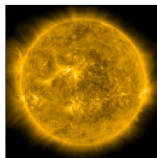
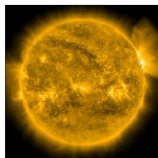
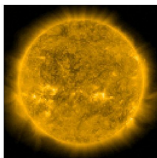
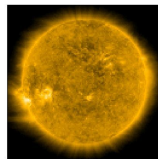
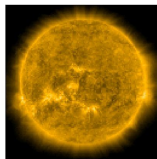
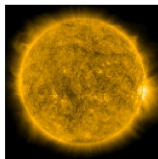
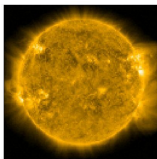
M accuracy



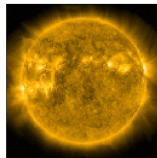
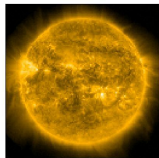
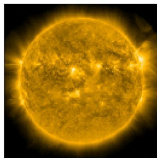
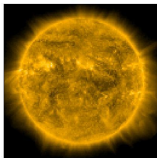
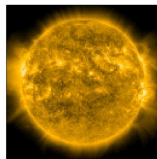
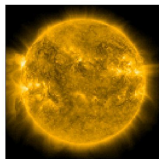
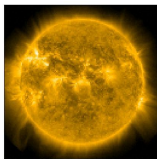
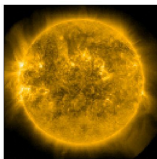
Low level activity 128x128



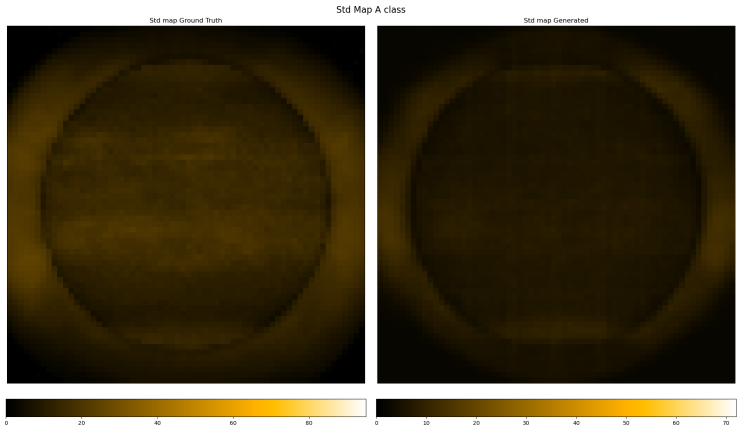
Medium level activity 128x128



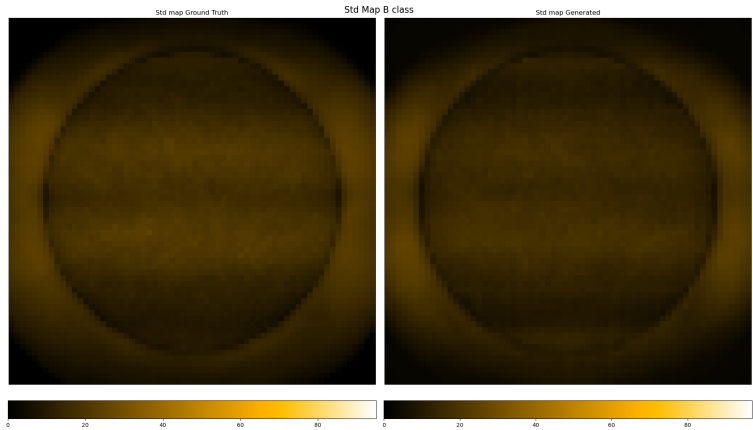
High level activity 128x128



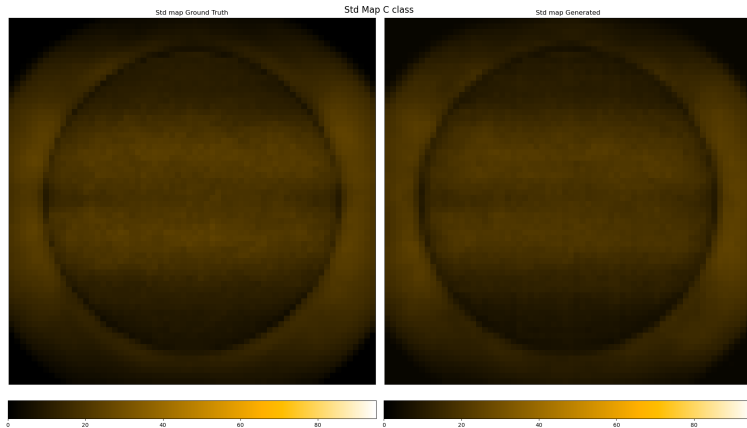
Std A



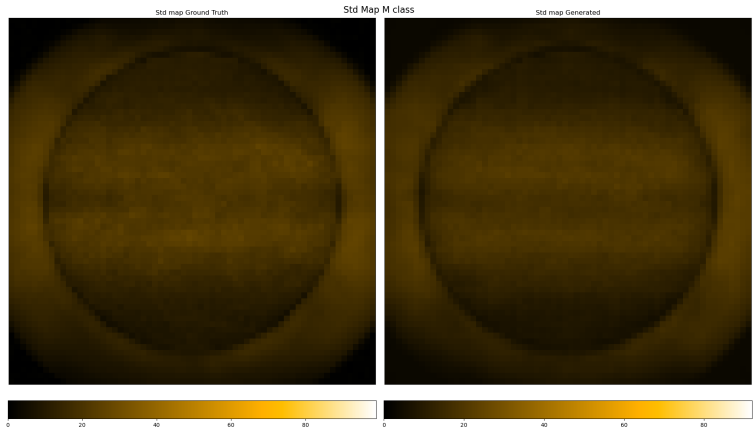
Std B



Std C



Std M



Std X

